



Women Professional Meet up - Face Challenges of Future Technologies

VENUE: RVR&JC College of Engineering, Chowdavaram, Guntur, Andhra Pradesh

Date: 23.12.2022 Time: 10:00am - 5:00pm Event Registration link: https://events.vtools.ieee.org/m/337516

<u>Time</u>	<u>Schedule</u> Venue: Seminar Hall, Digital Block
9:00am – 9:45am	Registrations at the Venue
10:00 am - 10:45 am	Inauguration On stage: Secretary &Correspondent, Principal, Vice-Principal, WIE Chair, WIE Vice chair, event coordinators, subsection representatives etc
10:45 am - 11:25 am	Keynote Topic: Innovations & Patents [Virtual Session] Sri N. Venkatesh Sr. Director, Engineering, Silicon Labs Vice- Chair IEEE Hyderabad Section
11:25 am - 11:40 am	Tea and Snacks Break
11:40 am - 12:20pm	Session I Creating a better version of self - A conscious process Dr. Sujatha Kodali Assistant Professor, Department of M&H
12:20 pm - 1:00 pm	Session II Professional societies/chapters benefits and Awards Speaker: Dr G. Sri Lakshmi Professor in EEE Department, CVR College of Engineering Chair , WIE Affinity group IEEE Hyderabad section
1:00 pm - 1:45 pm	Lunch
2:00 pm - 2:40 pm	Session III Entrepreneurial Competencies - Tribute to teamwork Dr. Radhika Sajja Associate Professor, Mechanical Engineering
2:40 pm - 3:20 pm	Session IV From Textile to e-scooters Ms. Chandini Chandana Co-Founder & CEO, AVERA Electric Vehicles
3:20 pm - 4:00 pm	Session V Benefits of being WIE Professional member, Professional societies/chapters benefits and Awards Hari Vardhagini Subhadra Vice - Chair , WIE Affinity group IEEE Hyderabad section
4:00 pm - 4:15 pm	Tea and Snacks Break
4:15 pm - 4:45 pm	Valedictory On stage: Principal, Vice-Principal, WIE Chair, WIE Vice chair, event coordinators, subsection representative etc

Event Coordinator & Student Branch Mentor : Dr. K.Swarnasri Prof. in EEE Treasurer, Guntur Subsection <u>swarnasrik@rvrjc.ac.in</u>, <u>swarna@ieee.org</u>

IEEE Student Branch Chair: Dr. P. Tripura Asst. Prof. in EEE <u>Tripura.pidikiti@gmail.com</u> <u>Tripura.pidikiti@ieee.org</u>